SDAS048D - DECEMBER 1989 - REVISED JANUARY 1995

- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- True Logic Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), Standard Plastic (N) and Ceramic (J) 300-mil DIPs, and Ceramic Flat (W) Packages

description

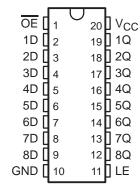
These octal D-type transparent latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

While the latch-enable (LE) input is high, outputs (Q) respond to the data (D) inputs. When LE is low, the outputs are latched to retain the data that was set up.

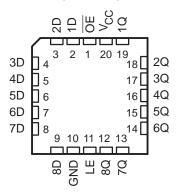
A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

SN54ALS573C, SN54AS573A . . . J OR W PACKAGE SN74ALS573C, SN74AS573A . . . DW OR N PACKAGE (TOP VIEW)



SN54ALS573C, SN54AS573A . . . FK PACKAGE (TOP VIEW)



The SN54ALS573C and SN54AS573A are characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS573C and SN74AS573A are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each latch)

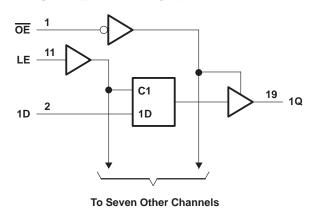
	INPUTS	OUTPUT	
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	X	Χ	Z

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logic symbol†

OE ΕN LE C1 2 19 1D 1D 1Q 3 18 2D 2Q 17 4 3D **3Q** 5 16 4D 4Q 6 15 5D 5Q 7 14 6D 6Q 8 13 7D **7Q** 9 12 8D 8Q

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T _A : SN54ALS573C	-55°C to 125°C
SN74ALS573C	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS573C			SN74ALS573C			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.7			0.8	V
ІОН	High-level output current			-1			-2.6	mA
l _{OL}	Low-level output current			12			24	mA
t _W	Pulse duration, LE high	25			10			ns
t _{su}	Setup time, data before LE↓	10			10			ns
th	Hold time, data after LE↓	7			7			ns
TA	Operating free-air temperature	-55		125	0		70	°C

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	TEST CONDITIONS		54ALS57	'3C	SN74ALS573C			UNIT
PARAMETER	1531 (4	DIDITIONS	MIN	TYP [†]	MAX	MIN	TYP†	MAX	UNII
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		
Voн	V _{CC} = 4.5 V	$I_{OH} = -1 \text{ mA}$	2.4	3.3					V
	vCC = 4.5 v	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
\/o.	V00 - 45 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL	V _{CC} = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V
lozh	$V_{CC} = 5.5 \text{ V},$	V _O = 2.7 V			20			20	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	V _O = 0.4 V			-20			-20	μΑ
l _l	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lіН	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20			20	μΑ
Ι _{ΙL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.13			-0.1	mA
1 ₀ ‡	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
		Outputs high		10	17		10	17	mA
Icc	V _{CC} = 5.5 V	Outputs low		15	24		15	24	
		Outputs disabled		16	27		16	27	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _I R1 R2 T _A	= 50 pF I = 500 Ω 2 = 500 Ω _ = MIN t	2, 2, o MAX§		UNIT
			SN54AL	S573C	SN74AL	S573C	
			MIN	MAX	MIN	MAX	
t _{PLH}	D	•	2	20	2	14	ns
t _{PHL}		Q	2	17	2	14	115
t _{PLH}	LE	_	8	33	6	20	ns
t _{PHL}	LL	Q	8	24	6	19	115
^t PZH		_	4	28	3	18	
tPZL	ŌĒ	Q	4	21	4	18	ns
^t PHZ	ŌĒ	Q	2	20	1	10	
t _{PLZ}	OE .	ď	3	26	1	15	ns

[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN54AS573A	-55°C to 125°C
SN74AS573A	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN	54AS573	BA	SN	74AS573	BA	UNIT
		MIN	NOM	MAX	MIN	NOM	MAX 5.5 0.8 -15 48	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V _{IH}	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.8			0.8	V
ІОН	High-level output current			-12			-15	mA
IOL	Low-level output current			32			48	mA
t _W *	Pulse duration, LE high	5.5			4.5			ns
t _{su} *	Setup time, data before LE↓	2			2			ns
th*	Hold time, data after LE↓	3			3			ns
TA	Operating free-air temperature	-55		125	0		70	°C

^{*} On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST C	ONDITIONS	SN	54AS57	3A	SN74AS573A			LINIT	
PARAMETER	TEST C	ONDITIONS	MIN	TYP [‡]	MAX	MIN	TYP‡	MAX	UNII	
VIK	$V_{CC} = 4.5 V,$	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V	
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	I _{OH} = −2 mA	V _{CC} -2	2		V _{CC} -2	2			
V_{OH}	V45V	$I_{OH} = -12 \text{ mA}$	2.4	3.2					V	
	V _{CC} = 4.5 V	$I_{OH} = -15 \text{ mA}$				2.4	3.3	-1.2 V -1.2		
Va	V 45V	I _{OL} = 32 mA		0.28	0.5				V	
VOL	V _{CC} = 4.5 V	I _{OL} = 48 mA					0.33	0.5	V	
lozh	$V_{CC} = 5.5 V,$	$V_0 = 2.7 \text{ V}$			50			50	μΑ	
lozL	$V_{CC} = 5.5 \text{ V},$	V _O = 0.4 V			-50			-50	μΑ	
lį	$V_{CC} = 5.5 V,$	V _I = 7 V			0.1			0.1	mA	
lіН	$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μΑ	
Ι _{ΙL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.5	mA	
ΙΟ§	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA	
		Outputs high		56	93		56	93		
ICC	V _{CC} = 5.5 V	Outputs low		55	90		55	90	mA	
		Outputs disabled		65	106		65	106		

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

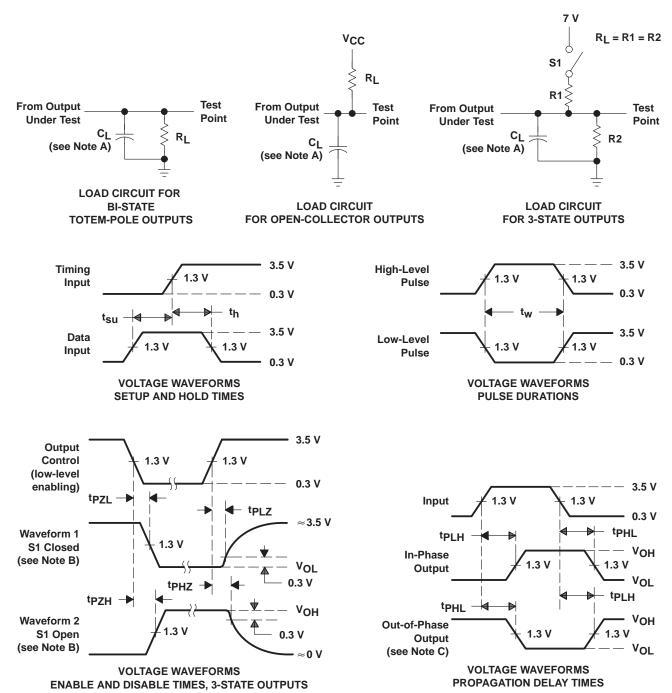
SN54ALS573C, SN54AS573A, SN74ALS573C, SN74AS573A OCTAL D-TYPE TRANSPARENT LATCHES WITH 3-STATE OUTPUTS SDAS048D - DECEMBER 1989 - REVISED JANUARY 1995

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T_A = MIN to MAX [†] SN54AS573A SN74AS57			C _L = 50 pF, R1 = 500 Ω , R2 = 500 Ω , T _A = MIN to MAX [†]		UNIT
			MIN	MAX	MIN	MAX		
^t PLH	D	_	3	11	3	8	ns	
t _{PHL}		Q	3	8	3	7	115	
^t PLH	LE	0	6	16.5	6	13	ns	
t _{PHL}	LE	Q	4	9	4	7.5	115	
^t PZH			2	8	2	6.5	20	
t _{PZL}	ŌĒ	Q	4	11	4	9.5	ns	
^t PHZ	ŌĒ	Q	2	8	2	6.5	ns	
t _{PLZ}	OE .	γ	2	8	2	7	115	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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